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Applicant(s)/Patent under Reexamination
ZHU ET AL.

Art Unit

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Examiner

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Mark A. Chapman

SEARCHED			
Class	Subclass	Date	Examiner
430	58.45	5/9/2005	МС
	58.05		
	59.4		
	64		
	66		
	126		
399	159		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
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